

# Reliability Report

Part Number: Transistors Series

Test Results : **PASS**

Test Item	Conditions	Duration	Quantity	Rejects
<b>TEST</b> Pre- and Post-Stress Electrical Test	T <sub>a</sub> = 25 °C	N/A	all parts	see below
* <b>Pre-conditioning</b>	1. Temperature Cycling:-40 °C ~60 °C, 2. Bake:125 °C, 3.1 Moisture Soak:85 °C , 85%RH for MSL3; OR 3.2 Moisture Soak:30 °C , 60%RH for MSL3; 4. Reflow*3Cycles:260 °C	5Cycles; 24 hours; 168hours 192hours 3Cycles	308Pcs	0
<b>HTRB</b> High Temperature Reverse Bias	MIL-STD-750 Method 1038 T <sub>j</sub> = T <sub>jmax</sub> , 80% VCBO	1000 hours	77Pcs	0
<b>TC</b> Temperature Cycling	JESD22-A104 -55 °C (+0,-10)/15Min~ 150(+15,-0)/15Min,	1000Cycles (500hours)	77Pcs	0
<b>AC</b> Autoclave	JESD22-A102 T <sub>a</sub> = 121 °C±2 °C , RH = 100 % , 15psig	96 hours	77Pcs	0
<b>H3TRB</b> High Humidity High Temperature Reverse Bias	JESD22-A101 T <sub>a</sub> = 85 °C±2 °C , RH = 85%±5% , 80 % VCBO (VCBO MAX=100V)	1000 hours	77Pcs	0
<b>IOL</b> Intermittent Operating Life	MIL-STD-750 Method 1037 ON 2Min/OFF 2min, devices powered to insure ,ΔT <sub>j</sub> ≥ 100 °C	15000 cycles (1000 hours)	77Pcs	0
<b>RSH</b> Resistance to Solder Heat	JESD22-B106 260 °C (+5 , -0)	10 s	30Pcs	0
<b>SD</b> Solderability	J-STD-002 235 °C ± 5 °C	3 s	10Pcs	0
<b>HTSL</b> High Temperature Storage Life	JESD22-A103 TstgMax	1000 hours	77Pcs	0

\*Remark : detail MSL of product refer to data sheet on MCC website.